

Notice of References Cited		Application/Control No. 09/731,579	Applicant(s)/Patent Under Reexamination TERRENCE RILEY ET AL.	
		Examiner Carlos Ortiz-Rodriguez	Art Unit 2125	Page 1 of 1

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	C	US-5,226,732	07-1993	Nakos et al.	374/133
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NON-PATENT DOCUMENTS

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	U	Poogyeon et al., "Control Strategy for Temperature Tracking in Rapid Thermal Processing of Semiconductor Wafers", Proceedings of the 31st Conference on Decision and Control; pages 2568-2573.
	V	Stuber et al., "Model-based Control of Rapid Thermal Processes", Proceedings of the 33rd Conference on Decision and Control; pages 79-85.
	W	Dilhac et al., "Thermal Modeling of a Wafer in a Rapid Thermal Processor", IEEE Transactions on Semiconductor Manufacturing; Vol 8, No.4, November 1995, 432-439.
	X	Gyugyi et al., "Control of Rapid Thermal Processing: A System Theoretic Approach", IEEE Transactions on Control Systems Technology; Vol 5, No.6, November 1997, 644-653.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.